PHP101NQ04T

N-channel TrenchMOS standard level FET

Rev. 02 — 5 March 2009

Product data sheet

1. Product profile

1.1 General description

Standard level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product is designed and qualified for use in computing, communications, consumer and industrial applications only.

1.2 Features and benefits

- Low conduction losses due to low on-state resistance
- Suitable for standard level gate drive sources

1.3 Applications

- DC-to-DC convertors
- General industrial applications
- Motors, lamps and solenoids
- Uninterruptible power supplies

1.4 Quick reference data

Table 1. Quick reference

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
V_{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C	-	-	40	V
I _D	drain current	$T_{mb} = 25 ^{\circ}\text{C}; V_{GS} = 10 \text{V};$ see <u>Figure 1</u> ; see <u>Figure 3</u>	-	-	75	Α
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	-	157	W
Dynamic	characteristics					
Q_{GD}	gate-drain charge	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $V_{DS} = 32 \text{ V}; T_j = 25 \text{ °C};$ see Figure 11	-	12.6	-	nC
Static ch	aracteristics					
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 25 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \underline{\text{Figure 9}};$ $\text{see } \underline{\text{Figure 10}}$	-	6.6	8	mΩ



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2. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		_
2	D	drain	mb	D
3	S	source		$G \longrightarrow \overline{A}$
mb	D	mounting base; connected to drain	1 2 3	mbb076 S
			SOT78 (TO-220AB; SC-46)	

3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
PHP101NQ04T	TO-220AB; SC-46	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78

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Limiting values

Table 4. **Limiting values**

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In accordance with the Absolute Maximum Rating System (IEC 60134).

Parameter	Conditions	Min	Max	Unit
drain-source voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}$	-	40	V
drain-gate voltage	$T_j \ge 25 \text{ °C}; T_j \le 175 \text{ °C}; R_{GS} = 20 \text{ k}\Omega$	-	40	V
gate-source voltage		-20	20	V
drain current	$V_{GS} = 10 \text{ V}; T_{mb} = 100 \text{ °C}; \text{ see } \frac{\text{Figure 1}}{\text{Model}}$	-	71	Α
	V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u> ; see <u>Figure 3</u>	-	75	Α
peak drain current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$; see Figure 3	-	240	Α
total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>	-	157	W
storage temperature		-55	175	°C
junction temperature		-55	175	°C
ruggedness				
non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 45 A; V_{sup} ≤ 55 V; unclamped; t_p = 0.17 ms; R_{GS} = 50 Ω	-	200	mJ
ain diode				
source current	T _{mb} = 25 °C	-	75	Α
peak source current	$t_p \le 10 \ \mu s$; pulsed; $T_{mb} = 25 \ ^{\circ}C$	-	240	Α
	drain-source voltage drain-gate voltage gate-source voltage drain current peak drain current total power dissipation storage temperature junction temperature ruggedness non-repetitive drain-source avalanche energy ain diode source current	drain-source voltage $T_j \ge 25 ^{\circ}\text{C}; T_j \le 175 ^{\circ}\text{C}$ drain-gate voltage $T_j \ge 25 ^{\circ}\text{C}; T_j \le 175 ^{\circ}\text{C}; R_{GS} = 20 \text{k}\Omega$ gate-source voltage drain current $V_{GS} = 10 \text{V}; T_{mb} = 100 ^{\circ}\text{C}; \text{see Figure 1}$ $V_{GS} = 10 \text{V}; T_{mb} = 25 ^{\circ}\text{C}; \text{see Figure 1};$ see Figure 3 peak drain current $t_p \le 10 \mu \text{s}; \text{pulsed}; T_{mb} = 25 ^{\circ}\text{C}; \text{see Figure 3}$ total power dissipation $T_{mb} = 25 ^{\circ}\text{C}; \text{see Figure 2}$ storage temperature junction temperature $T_{mb} = 25 ^{\circ}\text{C}; \text{see Figure 2}$ $T_{mb} = 25 ^{\circ}\text{C}; \text{see Figure 2}$ $T_{mb} = 25 ^{\circ}\text{C}; \text{see Figure 3}$ $T_{mb} = 25 ^{\circ}\text{C}; \text{see Figure 3}$ $T_{mb} = 25 ^{\circ}\text{C}; \text{see Figure 2}$ $T_{mb} = 25 ^{\circ}\text{C}; \text{see Figure 3}$	drain-source voltage $T_j \ge 25 ^{\circ}\text{C}; T_j \le 175 ^{\circ}\text{C}$ - drain-gate voltage $T_j \ge 25 ^{\circ}\text{C}; T_j \le 175 ^{\circ}\text{C}; R_{GS} = 20 \text{k}\Omega$ - gate-source voltage -20 drain current $V_{GS} = 10 \text{V}; T_{mb} = 100 ^{\circ}\text{C}; \text{see Figure 1}$ - $V_{GS} = 10 \text{V}; T_{mb} = 25 ^{\circ}\text{C}; \text{see Figure 1}; \text{see Figure 3}$ - total power dissipation $T_{mb} = 25 ^{\circ}\text{C}; \text{see Figure 2}$ - storage temperature -55 junction temperature -55 yunction temperature -55 vargedness -55 var	$ \begin{array}{llllllllllllllllllllllllllllllllllll$

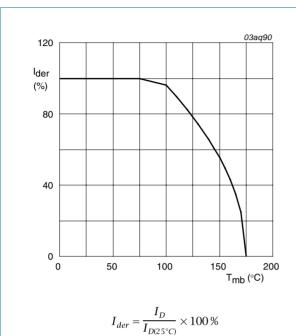
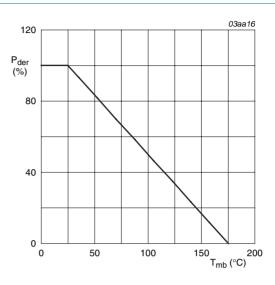
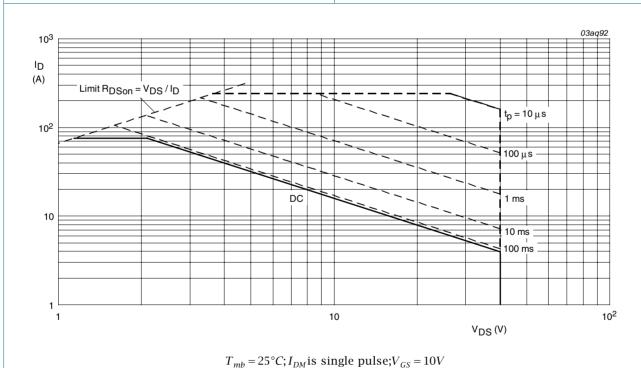


Fig 1. Normalized continuous drain current as a function of mounting base temperature



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

Normalized total power dissipation as a Fig 2. function of mounting base temperature



Safe operating area; continuous and peak drain currents as a function of drain-source voltage Fig 3.

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Thermal characteristics

Thermal characteristics Table 5.

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	see Figure 4	-	-	0.95	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	vertical in still air	-	60	-	K/W

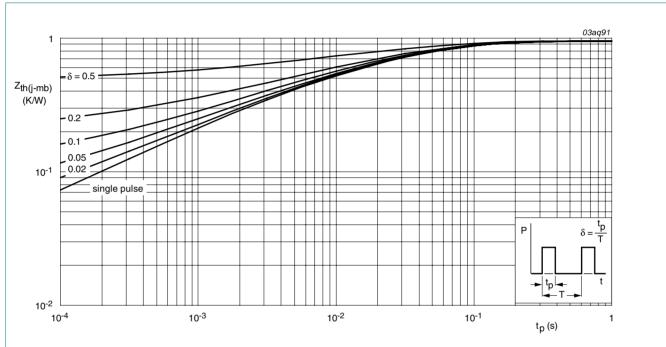


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

Characteristics

Table 6. Characteristics

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Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
V _{(BR)DSS}	drain-source	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = -55 °C$	36	-	-	V
	breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	40	-	-	V
55 ()	gate-source threshold voltage	$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = -55 \text{ °C}$; see <u>Figure 7</u> ; see <u>Figure 8</u>	-	-	4.4	V
		$I_D = 1 \text{ mA}$; $V_{DS} = V_{GS}$; $T_j = 175 \text{ °C}$; see <u>Figure 7</u> ; see <u>Figure 8</u>	1	-	-	V
		$I_D = 1$ mA; $V_{DS} = V_{GS}$; $T_j = 25$ °C; see <u>Figure 7</u> ; see <u>Figure 8</u>	2	3	4	V
I _{DSS}	drain leakage current	$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		$V_{DS} = 40 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 175 \text{ °C}$	-	-	500	μΑ
I _{GSS}	I _{GSS} gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	2	100	nA
R _{DSon} drain-source on-state resistance	drain-source on-state resistance	V_{GS} = 10 V; I_D = 25 A; T_j = 175 °C; see <u>Figure 9</u> ; see <u>Figure 10</u>	-	-	15.2	mΩ
		$V_{GS} = 10 \text{ V}$; $I_D = 25 \text{ A}$; $T_j = 25 \text{ °C}$; see <u>Figure 9</u> ; see <u>Figure 10</u>	-	6.6	8	mΩ
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$	-	36.6	-	nC
Q_{GS}	gate-source charge	T _j = 25 °C; see <u>Figure 11</u>	-	9.8	-	nC
Q_{GD}	gate-drain charge		-	12.6	-	nC
C _{iss}	input capacitance	$V_{DS} = 25 \text{ V}; V_{GS} = 0 \text{ V}; f = 1 \text{ MHz};$	-	2020	-	pF
Coss	output capacitance	T _j = 25 °C; see <u>Figure 12</u>	-	485	-	pF
C _{rss}	reverse transfer capacitance		-	215	-	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; R_L = 1.2 \Omega; V_{GS} = 10 \text{ V};$	-	20	-	ns
t _r	rise time	$R_{G(ext)} = 10 \Omega; T_j = 25 °C$	-	51	-	ns
t _{d(off)}	turn-off delay time		-	51	-	ns
t _f	fall time		-	33	-	ns
Source-d	rain diode					
V_{SD}	source-drain voltage	$I_S = 25 \text{ A}$; $V_{GS} = 0 \text{ V}$; $T_j = 25 \text{ °C}$; see <u>Figure 13</u>	-	0.85	1.2	V
t _{rr}	reverse recovery time	$I_S = 20 \text{ A}$; $dI_S/dt = -100 \text{ A/}\mu\text{s}$; $V_{GS} = 0 \text{ V}$;	-	53	-	ns
		$V_{DS} = 25 \text{ V}; T_i = 25 \text{ °C}$				

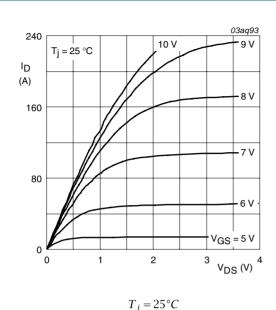


Fig 5. Output characteristics: drain current as a function of drain-source voltage; typical values

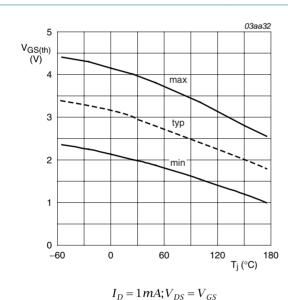
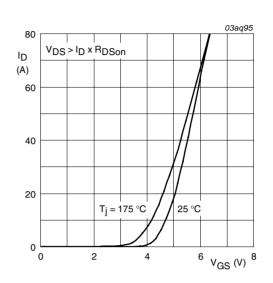


Fig 7. Gate-source threshold voltage as a function of junction temperature



 $T_j = 25$ °C and 175°C; $V_{DS} > I_D \times R_{DSon}$

Fig 6. Transfer characteristics: drain current as a function of gate-source voltage; typical values

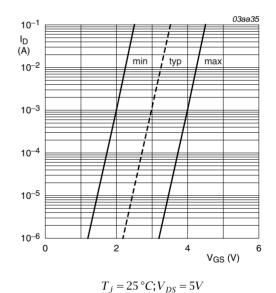
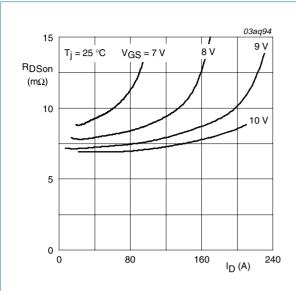


Fig 8. Sub-threshold drain current as a function of gate-source voltage



 $T_j = 25^{\circ}C$

Fig 9. Drain-source on-state resistance as a function of drain current; typical values

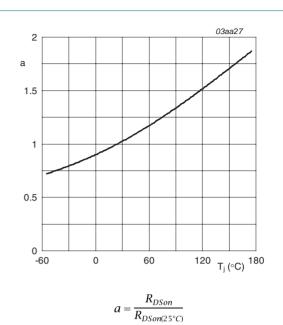
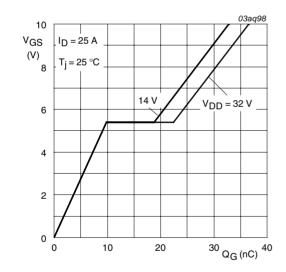
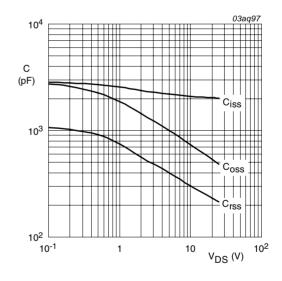


Fig 10. Normalized drain-source on-state resistance factor as a function of junction temperature



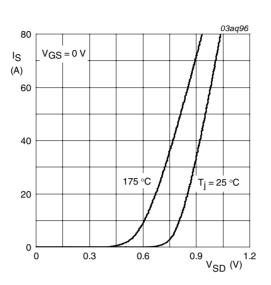
 $I_D = 25A$; $V_{DS} = 14V$ and 32V

Fig 11. Gate-source voltage as a function of gate charge; typical values



 $V_{GS} = 0V; f = 1MHz$

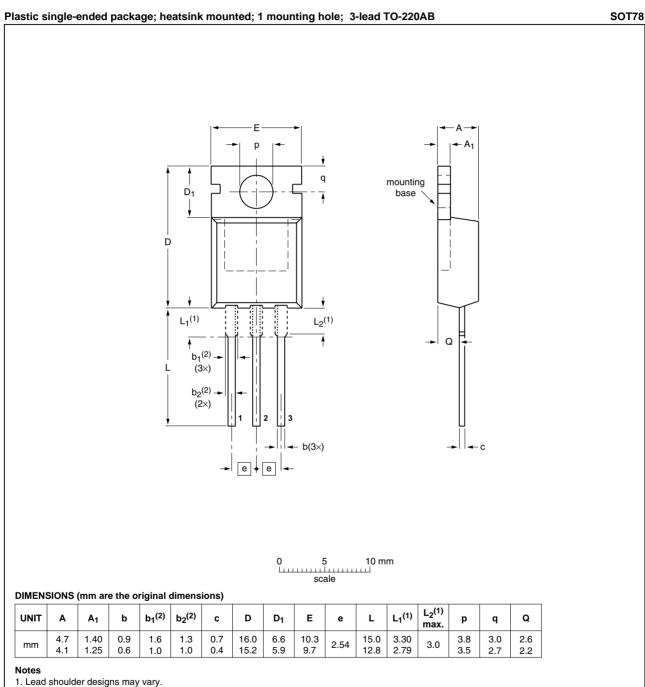
Fig 12. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



 $T_j = 25$ °C and 175°C; $V_{GS} = 0V$

Fig 13. Source current as a function of source-drain voltage; typical values

Package outline



- 2. Dimension includes excess dambar.

OUTLINE		REFER	ENCES	EUROPEAN	ISSUE DATE
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE
SOT78		3-lead TO-220AB	SC-46		08-04-23 08-06-13

Fig 14. Package outline SOT78 (TO-220AB)

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8. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
PHP101NQ04T_2	20090305	Product data sheet	-	PHP_PHB101NQ04T-01
Modifications:		of this data sheet has been of NXP Semiconductors.	n redesigned to comply w	ith the new identity
	 Legal texts 	have been adapted to the	new company name whe	re appropriate.
	 Type numb 	er PHP101NQ04T separat	ed from data sheet PHP_	PHB101NQ04T-01.
PHP_PHB101NQ04T-01 (9397 750 13167)	20040512	Product data	-	-

PHP101NQ04T

N-channel TrenchMOS standard level FET

9. Legal information

9.1 Data sheet status

Document status [1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
- [3] The product status of device(s) described in this document may have changed since this document was published and may differ in case of multiple devices. The latest product status information is available on the Internet at URL http://www.nxp.com.

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